

Multi-Beam systems and integrated in-situ techniques

Francesco BIANCARDI

FIBSEMs have been widely used thanks to their versatility and possibilities of integration with different techniques in several application fields, from TEM lamella preparation to Nanotomography and Nanofabrication. Today we present new ZEISS solutions that expand the Focused Ion Beam field into real Multi-Beam and Multi-Modal systems, introducing the new fs Laser-FIB technology and complementary techniques like integrated in-situ AFM, Raman spectroscopy and Correlative 3D Multi-Scale analysis.